

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1 Claim 1 (currently amended): An electrical test probe tip for use with a
2 probing head, comprising:

3 (a) a conductive flexible coil having a first end and a second end;

4 (b) said first end for coupling with a device to be probed; ~~[[and]]~~

5 (c) a connector attached to said second end of said conductive flexible
6 coil;

7 (d) said connector for connecting to said probing head; and

8 (e) said conductive flexible coil at least partially extending beyond said
9 probing head when said connector is connected to said probing
10 head.

1 Claim 2 (currently amended): The electrical test probe tip of claim 1, said
2 connector being a connecting pin coupleable to ~~[[a]]~~ said probing head.

1 Claim 3 (currently amended): The electrical test probe tip of claim 1, said
2 connector being a square pin coupleable to ~~[[a]]~~ said probing head.

1 Claim 4 (withdrawn): The electrical test probe tip of claim 1, said
2 connector being in integral connection with ~~[[a]]~~ said probing head.

1 Claim 5 (original): The electrical test probe tip of claim 1, said flexible coil
2 having a longitudinal axis and a first diameter, said first diameter being substantially
3 equal throughout said longitudinal axis of said flexible coil.

1 Claim 6 (withdrawn): The electrical test probe tip of claim 5, said first end
2 having a second diameter larger than said first diameter.

1 Claim 7 (withdrawn): The electrical test probe tip of claim 1, said first end
2 further comprising a hook.

1 Claim 8 (withdrawn): The electrical test probe tip of claim 1, said first end
2 further comprising a foot.

1 Claim 9 (withdrawn): The electrical test probe tip of claim 1 further
2 comprising an exterior conductive sheath at least partially surrounding said conductive
3 flexible coil.

1 Claim 10 (withdrawn): The electrical test probe tip of claim 1 further
2 comprising an exterior insulating sheath at least partially surrounding said conductive
3 flexible coil.

1 Claim 11 (withdrawn): The electrical test probe tip of claim 1 further
2 comprising a conductor disposed at least partially through the axial center of said
3 conductive flexible coil.

1 Claim 12 (withdrawn): The electrical test probe tip of claim 11, wherein
2 said conductor is made of a conductive elastomer.

1 Claim 13 (currently amended): A multipurpose electrical test probe tip
2 interconnectable with a probing head, comprising:

- 3 (a) a conductive flexible member;
- 4 (b) said flexible member having a first end and a second end;
- 5 (c) said flexible member being substantially hollow at said first end;
- 6 and
- 7 (d) said first end of said conductive flexible member for securely
- 8 flexibly coupling with a component to be probed so as to allow
- 9 movement of said probing head.

1 Claim 14 (currently amended): The multipurpose electrical test probe tip
2 of claim 13, wherein said second end of said conductive flexible member is
3 interconnectable with [[a]] said probing head.

1 Claim 15 (withdrawn): The multipurpose electrical test probe tip of claim
2 14, wherein said second end of said conductive flexible member is integral with said
3 probing head.

1 Claim 16 (original): The multipurpose electrical test probe tip of claim 14,
2 said second end of said conductive flexible member further comprising a connector
3 coupleable with said probing head.

1 Claim 17 (original): The multipurpose electrical test probe tip of claim 13,
2 said flexible member having a longitudinal axis and a first diameter, said first diameter
3 being substantially equal throughout said longitudinal axis of said flexible coil.

1 Claim 18 (withdrawn): The multipurpose electrical test probe tip of claim
2 17, said first end having a second diameter larger than said first diameter.

1 Claim 19 (withdrawn): The multipurpose electrical test probe tip of claim
2 13, said first end further comprising a hook.

1 Claim 20 (withdrawn): The multipurpose electrical test probe tip of claim
2 13, said first end further comprising a foot.

1 Claim 21 (withdrawn): The multipurpose electrical test probe tip of claim 1
2 further comprising an exterior conductive sheath at least partially surrounding said
3 conductive flexible member.

1 Claim 22 (withdrawn): The multipurpose electrical test probe tip of claim 1
2 further comprising an exterior insulating sheath at least partially surrounding said
3 conductive flexible member.

1 Claim 23 (withdrawn): The multipurpose electrical test probe tip of claim 1
2 further comprising a conductor disposed at least partially through the axial center of said
3 conductive flexible member.

1 Claim 24 (withdrawn): A method for using a multipurpose electrical test
2 probe having a probing head, said method comprising the steps of:

3 (a) providing a flexible spring tip, said flexible spring tip having a
4 connector end connectable to said probing head and a flexible coil
5 contact end remote from said probing head;

6 (b) connecting said connector end to said probing head; and

7 (c) placing said contact end in flexible electrical contact with an
8 electrical component to be probed so as to permit movement of
9 said probing head.

1 Claim 25 (withdrawn): The method of claim 24, wherein said step of
2 connecting said connector end to said probing head further comprises the step of
3 permanently connecting said connector end to said probing head.

1 Claim 26 (withdrawn): The method of claim 24 further comprising the step
2 of flexing said flexible spring tip while said contact end is in flexible electrical contact
3 with said electrical component so as to allow access to a nearby electrical component.

1 Claim 27 (withdrawn): The method of claim 24 further comprising the step
2 of flexing said flexible spring tip while said contact end is in flexible electrical contact
3 with said electrical component so as to allow access to a nearby ground component.

1 Claim 28 (previously presented): The electrical test probe tip of claim 1,
2 said conductive flexible coil being substantially hollow at said first end.

1 Claim 29 (previously presented): The electrical test probe tip of claim 1,
2 said conductive flexible coil being substantially hollow.

1 Claim 30 (previously presented): The electrical test probe tip of claim 1,
2 said first end of said conductive flexible coil being suitable to receive a device to be
3 probed therein.

1 Claim 31 (currently amended): The electrical test probe tip of claim 1,
2 wherein said first end of said conductive flexible coil at least partially surrounds a device
3 to be ~~probe~~ probed.

1 Claim 32 (previously presented): The multipurpose electrical test probe tip
2 of claim 13, said conductive flexible member being substantially hollow.

1 Claim 33 (previously presented): The multipurpose electrical test probe tip
2 of claim 13, said first end of said conductive flexible member being suitable to receive a
3 component to be probed therein.

1 Claim 34 (previously presented): The multipurpose electrical test probe tip
2 of claim 13, wherein said first end of said conductive flexible member at least partially
3 surrounds a component to be probed.

1 Claim 35 (new): The electrical test probe tip of claim 1, said first end of
2 said flexible coil having at least one additional coupling mechanism extending
3 therefrom, said additional coupling mechanism selected from the group consisting of:

- 4 (a) an enlarged coil having a diameter larger than the diameter of said
5 flexible coil;
6 (b) a hook; and
7 (c) a foot.

1 Claim 36 (new): The electrical test probe tip of claim 13, said first end of
2 said flexible coil having at least one additional coupling mechanism extending
3 therefrom, said additional coupling mechanism selected from the group consisting of:

- 4 (a) an enlarged coil having a diameter larger than the diameter of said
5 flexible coil;
6 (b) a hook; and
7 (c) a foot.

1 Claim 37 (new): A probing system, said system comprising:

2 (a) an electrical test probe tip, comprising:

3 (i) a conductive flexible coil having a first end and a second
4 end;

5 (ii) said first end for coupling with a device to be probed; and

6 (iii) a connector attached to said second end of said conductive
7 flexible coil;

8 (b) a probing head;

9 (c) said connector for connecting to said probing head; and

10 (d) said conductive flexible coil at least partially extending beyond said
11 probing head when said connector is connected to said probing
12 head.

1 Claim 38 (new): A probing system, said system comprising:

2 (a) a multipurpose electrical test probe tip, comprising:

3 (i) a conductive flexible member;

4 (ii) said flexible member having a first end and a second end;
5 and

6 (iii) said flexible member being substantially hollow at said first
7 end;

8 (b) a probing head;

9 (c) said multipurpose electrical test probe tip interconnectable with said
10 probing head; and

11 (d) said first end of said conductive flexible member for securely
12 flexibly coupling with a component to be probed so as to allow
13 movement of said probing head.